- **Inputs Are TTL Compatible**
- *EPIC*™ **(Enhanced-Performance Implanted CMOS) 1-μm Process**
- **Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and DIP (N) Packages, Ceramic Chip Carriers (FK), Flat (W), and DIP (J) Packages**

SN54ACT241 . . . J OR W PACKAGE
SN74ACT241 . . . DB, DW, N, OR PW PACKAGE
(TOP VIEW)

```
1OE  [ 1      20 ] VCC
1A1  [ 2      19 ] 2OE
2Y4  [ 3      18 ] 1Y1
1A2  [ 4      17 ] 2A4
2Y3  [ 5      16 ] 1Y2
1A3  [ 6      15 ] 2A3
2Y2  [ 7      14 ] 1Y3
1A4  [ 8      13 ] 2A2
2Y1  [ 9      12 ] 1Y4
GND  [ 10     11 ] 2A1
```
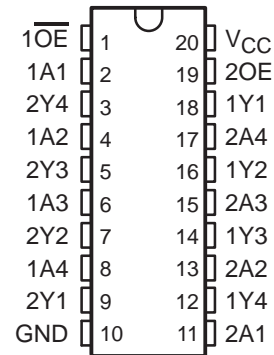
description

These octal buffers and line drivers are designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.
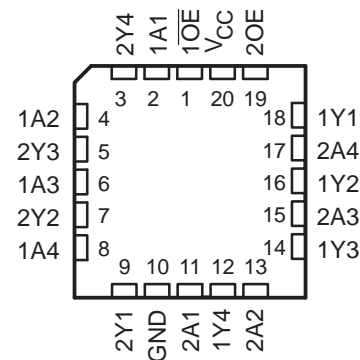
The 'ACT241 are organized as two 4-bit buffers/drivers with separate complementary output-enable (1OE and 2OE) inputs. When 1OE is low or 2OE is high, the device passes noninverted data from the A inputs to the Y outputs. When 1OE is high or 2OE is low, the outputs are in the high-impedance state.

The SN54ACT241 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ACT241 is characterized for operation from –40°C to 85°C.

SN54ACT241 . . . FK PACKAGE
(TOP VIEW)

```
       2Y4 1A1 1OE VCC 2OE
        3   2   1  20  19
1A2 [ 4              18 ] 1Y1
2Y3 [ 5              17 ] 2A4
1A3 [ 6              16 ] 1Y2
2Y2 [ 7              15 ] 2A3
1A4 [ 8              14 ] 1Y3
        9  10  11  12  13
       2Y1 GND 2A1 1Y4 2A2
```

FUNCTION TABLES

INPUTS		OUTPUT
1OE	1A	1Y
L	H	H
L	L	L
H	X	Z

INPUTS		OUTPUT
2OE	2A	2Y
H	H	H
H	L	L
L	X	Z

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

EPIC is a trademark of Texas Instruments Incorporated.

Copyright © 1996, Texas Instruments Incorporated

TEXAS INSTRUMENTS
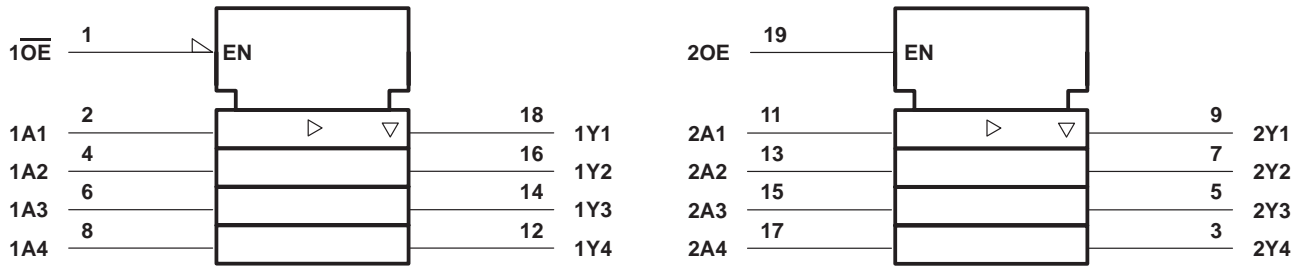
logic symbol[†]

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)
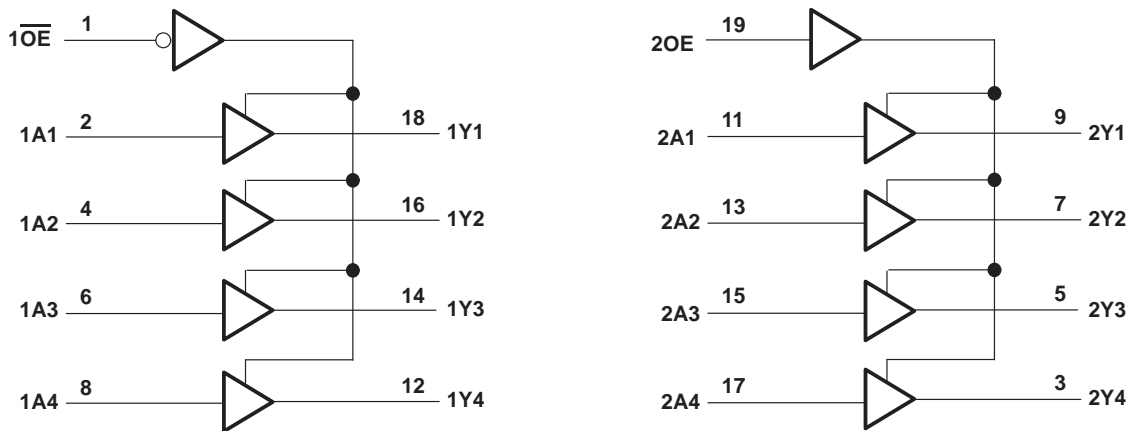
absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V_{CC} .... −0.5 V to 7 V
Input voltage range, V_I (see Note 1) .... −0.5 V to V_{CC} + 0.5 V
Output voltage range, V_O (see Note 1) .... −0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} (V_I < 0 or V_I > V_{CC}) .... ±20 mA
Output clamp current, I_{OK} (V_O < 0 or V_O > V_{CC}) .... ±20 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) .... ±50 mA
Continuous current through V_{CC} or GND .... ±200 mA
Maximum power dissipation at T_A = 55°C (in still air) (see Note 2): DB package .... 0.6 W
                                                                    D package .... 1.6 W
                                                                    N package .... 1.3 W
                                                                    PW package .... 0.7 W
Storage temperature range, T_{stg} .... −65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1.   The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
         2.   The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

TEXAS
INSTRUMENTS

recommended operating conditions (see Note 3)

		SN54ACT241		SN74ACT241		UNIT
		MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage	4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage	2		2		V
V_{IL}	Low-level input voltage		0.8		0.8	V
V_I	Input voltage	0	V_{CC}	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current		−24		−24	mA
I_{OL}	Low-level output current		24		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	8	0	8	ns/V
T_A	Operating free-air temperature	−55	125	−40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	T_A = 25°C			SN54ACT241		SN74ACT241		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}	I_{OH} = −50 µA	4.5 V	4.4	4.49		4.4		4.4		V
		5.5 V	5.4	5.49		5.4		5.4		
	I_{OL} = −24 mA	4.5 V	3.86			3.7		3.76		
		5.5 V	4.86			4.7		4.76		
	I_{OH} = −50 mA†	5.5 V				3.85				
	I_{OH} = −75 mA†	5.5 V						3.85		
V_{OL}	I_{OL} = 50 µA	4.5 V		0.001	0.1		0.1		0.1	V
		5.5 V		0.001	0.1		0.1		0.1	
	I_{OL} = 24 mA	4.5 V			0.36		0.5		0.44	
		5.5 V			0.36		0.5		0.44	
	I_{OL} = 50 mA†	5.5 V					1.65			
	I_{OL} = 75 mA†	5.5 V							1.65	
I_{OZ}	V_O = V_{CC} or GND	5.5 V			±0.25		±5		±2.5	µA
I_I	V_I = V_{CC} or GND	5.5 V			±0.1		±1		±1	µA
I_{CC}	V_I = V_{CC} or GND, I_O = 0	5.5 V			4		80		40	µA
ΔI_{CC}‡	One input at 3.4 V, Other inputs at GND or V_{CC}	5.5 V		0.6			1.6		1.5	mA
C_i	V_I = V_{CC} or GND	5 V		2.5						pF
C_o	V_I = V_{CC} or GND	5 V		8						pF

† Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.
‡ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

TEXAS
INSTRUMENTS

## switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			SN54ACT241		SN74ACT241		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A	Y	1.5	6	8.5	1	9.5	1.5	9.5	ns
t_{PHL}			1.5	5.5	7.5	1	9	1.5	8.5	
t_{PZH}	$\overline{OE}$ or OE	Y	1.5	7	8.5	1	10	1	9.5	ns
t_{PZL}			2	7	9.5	1	11.5	1.5	10.5	
t_{PHZ}	$\overline{OE}$ or OE	Y	2	8	9.5	1	11	2	10.5	ns
t_{PLZ}			2.5	6.5	10	1	11.5	2	10.5	

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance per buffer/driver	C_L = 50 pF, f = 1 MHz	45	pF

PARAMETER MEASUREMENT INFORMATION
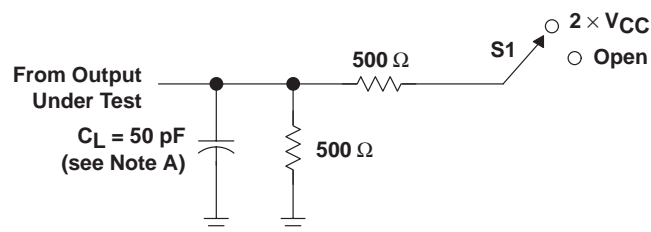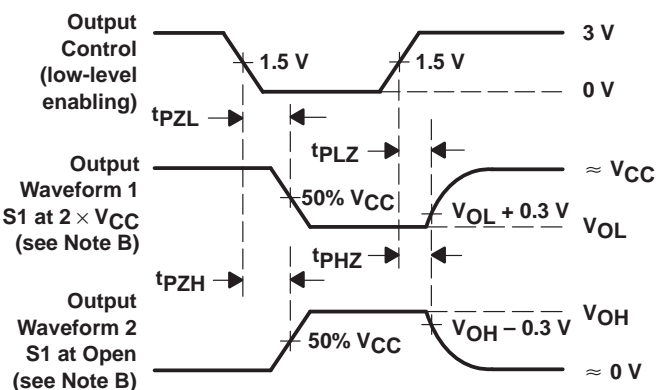

TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	Open

LOAD CIRCUIT
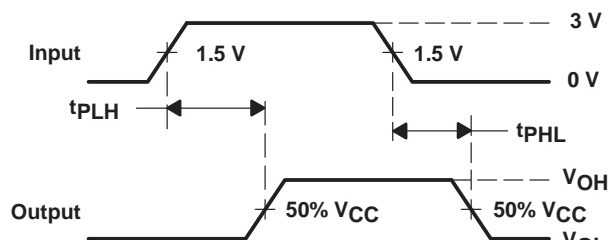
VOLTAGE WAVEFORMS

VOLTAGE WAVEFORMS

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.